



System for monitored run-in of infrared sensors

Product description

In the system, up to 200 infrared sensors can be subjected to a monitored run-in.

Up to four thermally defined carrier plates with a capacity of ten sensors each are placed on five levels. Temperature control is carried out by a temperature control unit using temperature control fluid for all five levels.

Field of application

Manufacturing/Production of infrared sensors



System for monitored run-in of infrared sensors

Technical data

Test bench/device

- Temperature control chamber made of aluminium profile
 - Safety door
 - 20 exchangeable carrier plates for the specimen
- Temperature control unit
- Measuring and testing technology in 19"/16 HU rack

Software

- Firmware IR-RUN on μ controller
- Serial interface for the output of measurement data

Scope of testing

- Sequential measurement of 200 specimen
 - Current consumption cooler, 0 – 3 A
 - Current consumption ir diode cell, 0 – 250 mA
 - Temperature, 10 °C – 100 °C, $\pm 0,1$ %
- Control of specimen temperature with liquid-temperature-controlled carrier plates, -30 °C - +48 °C, $\pm 0,1$ °K
- Monitoring current, voltage and temperature

Input-/visualisation units

- 1x control panel with 4-line LCD display
- Membrane keypad for recording the sequence of operations and limit values
- 20x LCD display, in the two measuring inserts
- Status LED per carrier plate
- Self-test switch per supply channel

Dimensions/Transport

- ca. 850x1900x1200 mm (WxHxD)

Test time

- Approx. 2 s per carrier plate

Exemplary device type

- 108 0007